



THE NEW LEVEL OF COATING THICKNESS MEASUREMENT

Do you want maximum efficiency in your quality control? Do you have to measure coating thicknesses highly reliable and precise? Our new FISCHERSCOPE® XDV® with XRF technology and the cutting-edge FISIQ® X software is your solution!

Super-fast sample positioning.

High-speed Z-axis 6 x faster*

Rapid sample capture.

Autofocus in under 2 seconds – 14 x faster*

Automated operation.

Automated or manual hood for maximum flexibility

Unparalleled high precision and repeatable results.

Optimized measurement geometry

Optimum sample illumination and picture capture.

10x higher* camera resolution and multizone LED lighting

Device status always visible.

Intuitive 180° status light

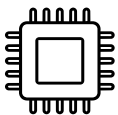
Enhanced usability and user guidance.

New FISIQ® X software

*In comparison to FISCHERSCOPE® X-RAY XDV®-SDD.

Designed for an exceptionally wide range of applications

High-end XRF instrument for measuring thin and very thin layers, including <math><0.05 \mu\text{m}</math>, in many different industries.



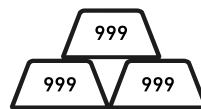
Semiconductors

Measure ultrathin layers/ metallization on wafers for development and process control.



Energy & automotive

Optimized measurements for fuel cell and battery materials.



Banking, customs & jewelry

Accurate analysis of precious metals, coins and jewelry.



Defence

Measurements of special coating systems and high reliability electronics

And many more...

Explore the new FISCHERSCOPE® XDV®!

glow-up.helmut-fischer.com



- ✓ Measure fast
- ✓ Measure precise
- ✓ Measure efficient



FISCHER – globally leading in highly precise XRF measuring technology.



Boost your productivity with simplified and efficient workflows

FISIQ® X – THE FIRST XRF SOFTWARE WITH AI TECHNOLOGY



With our FISCHERSCOPE® XDV® and FISIQ® X software, you measure coating thickness up to 6x faster* – thanks to improved algorithms and AI-supported spectrum analysis. Measure smarter, faster, and more user-friendly now!

- ✓ **Simplified and modern user interface**
- ✓ **Guided and efficient workflows**
- ✓ **Various user roles**

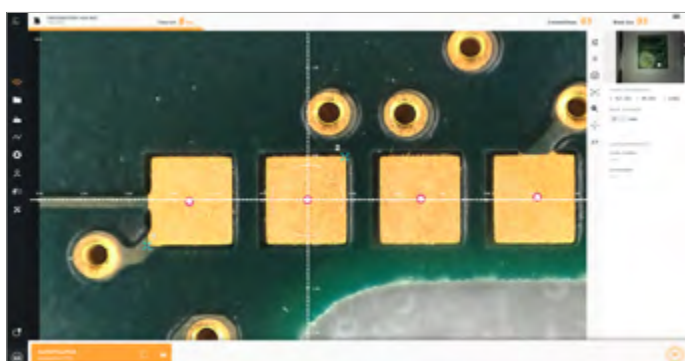
*Comparison calculation time between WinFTM® 6 and FISIQ® X.

From inserting the sample to precise measuring results – in no time at all.



1. Calibrate quickly and easily.

Measure your standards with the simple and guided calibration workflow and benefit from the ready-to-use standard library.



3. Measure with full control.

Place your sample and start the measuring program. See a live image and all relevant information clearly displayed for instant insights.



2. Build secure workflows.

Predefine your measuring program effortlessly with drag-and-drop to enhance your process safety and ensure consistent, repeatable results.



4. Obtain your results, ready to use.

Get instant element identification, view all results at a glance, and generate your report in just a few clicks.



Experience the new measuring solution now!
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